



Dr. Tae Yong Lee

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Tae Yong Lee is a principal member of the technical staff at imec in Belgium. He majored in Quantum Optics at Korea University and received his Management of Technology (MOT) Ph.D. degree from Sungkyunkwan University in Korea. He joined imec in 2023 and works in the field of Defectivity technology for the Advanced Technology Platforms. Prior to joining imec, he worked as a principal engineer and technical leader in Defect Inspection and Metrology to develop next generation devices at Semiconductor R&D Center, Samsung Electronics from 2000 to 2022.

His main areas of expertise include Yield Enhancement, Defect Detection, Wafer Inspection & Metrology, Process Integration, Process Development and Project Management. He developed and transferred new devices to high volume manufacturing as a member of EUV lithography patterning technology TF for next generation Memory, Metrology & Inspection (MI) bottleneck technology TF for LOGIC, and Project Management (PM) group for DRAM. As an MI technology expert and technology trend analyst, he worked with equipment suppliers to develop and evaluate next-generation metrology and inspection (optical, e-beam) technologies through JDP/JEP.